

Figure 1

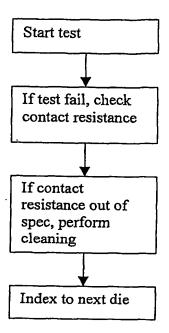


Figure 2

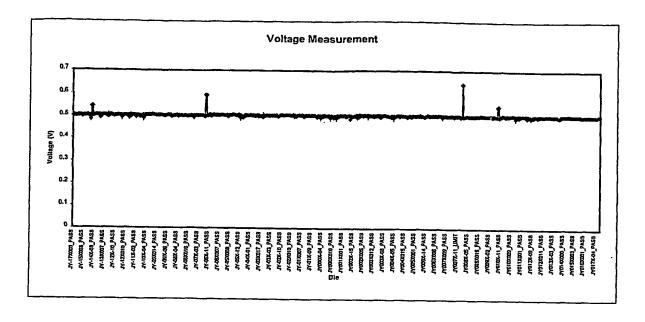
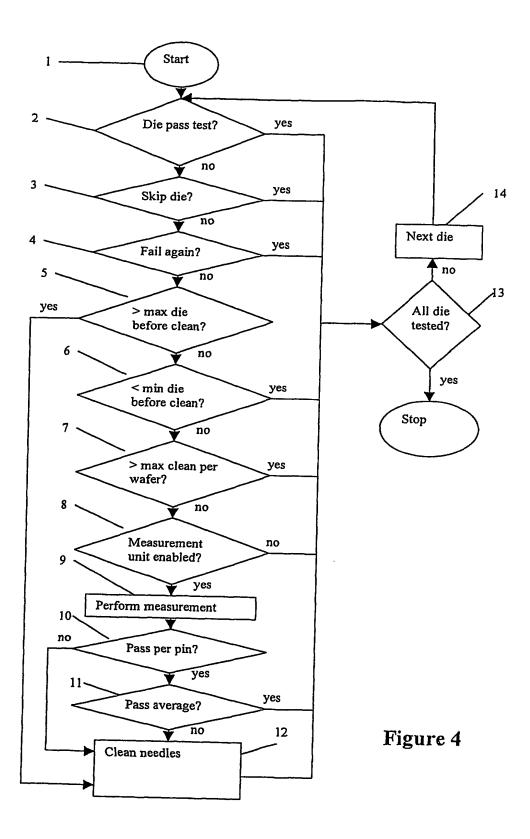


Figure 3



SUBSTITUTE SHEET (RULE 26)

16388.1_06.20	021001011407										<u>To.</u>
. Yil Device's	TMF105_wr1_112_12_12_12_12_12_12_12_12_12_12_12_1				Tes	ter :	D342X [199] 高级 [1] 10 10 10 10 10 10 10 10 10 10 10 10 10				=
高級 Lot ID :	s16388 17 6	Board Num	i	表 了	ouchdo	ໝາ້ະ	1072	FASSES PMU	Measu		5
Édix Wafer ID':	06年4月1日	Probe Card :	37,	Indexing		987	MARKET PARK	Cleanir	10.2	2	
Operator ID :		Test Mode :			Good Die :			Recovery :			3
Timestamp :	20021001011407 RRR: 0.33										
representation and	阿拉斯斯斯	Bin to Bin Recovery	Čc	unt	496. ∱	SUSEE SUSE SUSEE SUSEE SUSEE SUSEE SUSEE SUSEE SUSEE SUSEE SUSEE SUSEE SUSE SUSEE SUSEE SUSEE SUSEE SUSEE SUSEE SUS SUS	*** Top 10	CRC Fail Pins	Count	111 01	=
IDD_FAIL(7) -> SCAN_SP_FAIL(16)				1	0.11	xo(73) 2			40.00		
BIST_NOM_FAIL(8) -> GOOD(1)				1	0.11					40.	00
OPEN_FAIL(2) -> GOOD(1)				1	0.11		gdk1(2) 2			40.	00
AMCLK(19) -> GOOD(1)				1	0.11		gclk(1) 2 40			40.	00
	-	FAIL -> GOOD	Τ	3	0.34						<u> </u>

Figure 5